

SPECIFICATION

- Supplier : Samsung electro-mechanics
- Product : Multi-layer Ceramic Capacitor

- Samsung P/N : **CL03C5R6BA3GNND**
- Description : **CAP, 5.6pF, 25V, ±0.1 pF, C0G, 0201**

A. Samsung Part Number

CL
 03
 C
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 ① ② ③ ④ ⑤ ⑥ ⑦ ⑧ ⑨ ⑩ ⑪

① Series	Samsung Multi-layer Ceramic Capacitor		
② Size	0201 (inch code)	L: 0.6 ± 0.03 mm	W: 0.3 ± 0.03 mm
③ Dielectric	C0G	⑧ Inner electrode	Cu
④ Capacitance	5.6 pF	Termination	Cu
⑤ Capacitance tolerance	±0.1 pF	Plating	Sn 100% (Pb Free)
⑥ Rated Voltage	25 V	⑨ Product	Normal
⑦ Thickness	0.3 ± 0.03 mm	⑩ Special	Reserved for future use
		⑪ Packaging	Cardboard Type, 13" reel

B. Samsung Reliability Test and Judgement condition

	Performance	Test condition
Capacitance	Within specified tolerance	1MHz±10% 0.5~5Vrms
Q	512 min	
Insulation Resistance	10,000Mohm or 500Mohm·μF Whichever is Smaller	Rated Voltage 60~120 sec.
Appearance	No abnormal exterior appearance	Microscope (×10)
Withstanding Voltage	No dielectric breakdown or mechanical breakdown	300% of the rated voltage
Temperature Characterisitcs	C0G (From -55℃ to 125℃, Capacitance change should be within ±30PPM/℃)	
Adhesive Strength of Termination	No peeling shall be occur on the terminal electrode	200g·F, for 10±1 sec.
Bending Strength	Capacitance change : within ±5% or ±0.5pF whichever is larger	Bending to the limit (1mm) with 1.0mm/sec.
Solderability	More than 75% of terminal surface is to be soldered newly	1) Sn63Pb37 solder 235±5℃, 5±0.5sec. 2) SnAg3.0Cu0.5 solder 245±5℃, 3±0.3sec. (preheating : 80~120℃ for 10~30sec.)
Resistance to Soldering heat	Capacitance change : within ±2.5% or ±0.25pF whichever is larger Tan δ, IR : initial spec.	Solder pot : 270±5℃, 10±1sec.

	Performance	Test condition
Vibration Test	Capacitance change : within $\pm 2.5\%$ or $\pm 0.25\mu\text{F}$ whichever is larger Tan δ , IR : initial spec.	Amplitude : 1.5mm From 10Hz to 55Hz (return : 1min.) 2hours \times 3 direction (x, y, z)
Humidity	Capacitance change : within $\pm 5\%$ or $\pm 0.5\mu\text{F}$ whichever is larger Q : 256 min IR : 1000Mohm or 50Mohm $\cdot \mu\text{F}$ Whichever is Smaller	40 \pm 2 $^{\circ}\text{C}$, 90~95%RH, 500+12/-0hrs
Moisture Resistance	Capacitance change : within $\pm 7.5\%$ or $\pm 0.75\mu\text{F}$ whichever is larger Q : 118.67 min IR : 500Mohm or 25Mohm $\cdot \mu\text{F}$ Whichever is Smaller	With rated voltage 40 \pm 2 $^{\circ}\text{C}$, 90~95%RH, 500+12/-0hrs
High Temperature Resistance	Capacitance change : within $\pm 3\%$ or $\pm 0.3\mu\text{F}$ whichever is larger Q : 256 min IR : 1000Mohm or 50Mohm $\cdot \mu\text{F}$ Whichever is Smaller	With 200% of the rated voltage Max. operating temperature 1000+48/-0hrs
Temperature Cycling	Capacitance change : within $\pm 2.5\%$ or $\pm 0.25\mu\text{F}$ whichever is larger Tan δ , IR : initial spec.	1 cycle condition Min. operating temperature \rightarrow 25 $^{\circ}\text{C}$ \rightarrow Max. operating temperature \rightarrow 25 $^{\circ}\text{C}$ 5 cycle test

C. Recommended Soldering method :

Reflow (Reflow Peak Temperature : 260+0/-5 $^{\circ}\text{C}$, 10sec. Max)

* For the more detail Specification, Please refer to the Samsung MLCC catalogue.